

**Notice of References Cited**Application/Control No.  
09/683,857Applicant(s)/Patent Under  
Reexamination  
CHEN ET AL.Examiner  
David L. HogansArt Unit  
2813

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**NON-PATENT DOCUMENTS**

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	U	Quirk et al., Semiconductor Manufacturing Technology (2001), Prentice Hall, pages 228, 229 and 348
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\*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)  
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